Punishment of officers using sub-standard material in production of arms and ammunition

*118. SHRI SURESH KALMADI: Will the Minister of DEFENCE be pleased to state:

(a) whether Government propose to formulate a procedure to fix responsibility and to award punishment to officers found guilty of using sub-standard material in production of arms and ammunition;

(b) if so, the details thereof; and

(c) if not, the reasons therefor?

THE MINISTER OF DEFENCE (SHRI K. C. PANT): (a) to (c) Procedure already exists to fix responsibility and to award punishment to officers found guilty of using sub-standard material in production.

2. All material used in production of Arms and Ammunition is duly inspected before such use.

3. Procedure for quality assurance is designed on a three-tier system of inspection. First stage is the inspection of material at the supplier's premises by an inspection team headed by a Non-gazetted Officer of Directorate General of Quality Assurance. At the second stage, confirmatory inspection is carried out, also at supplier's premises, by a Gazetted Officer or a senior Non-gazetted Officer'. Where the first-tier inspection is on sample basis, the confirming officer draws 50 per cent of the samples taken for the first-tier inspection and an equal portion from the uninspected bulk of the lot. In the third stage, where it is required, considering the criticality of the item, samples are taken out on random basis for laboratory tests. Results of the inspection at different stages are submitted to the Head of the Quality Assurance Establishment for decision on acceptance of lots.

4. Under a system of defect investigation in force, where defect reports are received from users by the Directorate General of Quality Assurance, the causes of failure are identified and corrective measures are taken, as also, action to fix responsibility for human failure or negligence etc., if any.

Set-back in production of LSI and VLSI Chips due to fire

*119. SHRI SHANKER SINH VAGHELA:
SHRI PRAMOD MAHAJAN:

Will the PRIME MINISTER be pleased to state:

(a) the estimated loss and the setback in production programme of LSI and VLSI chips for the electronic industry due to the recent fire at the assembly section of the public sector Semi-conductor Complex Ltd., at Mohali near Chandigarh on the 7th February, 1989; and

(b) the steps taken to make-up the loss find with what results?

THE MINISTER OF STATE IN THE MINISTRY OF SCIENCE AND TECHNOLOGY AND THE MINISTER OF STATE IN THE DEPARTMENTS OF OCEAN DEVELOPMENT ATOMIC ENERGY, ELECTRONICS AND SPACE (SHRI K. R. NARAYANAN): (a) The fire at Semiconductor Complex Limited (SCL), SAS Nagar, Punjab, has destroyed the LSI/VLSI chips manufacturing and R and D facilities. The estimated loss is Rs. 60 crores.

(b) An Interim Action Plan to ensure continuity of supply of LSI/VLSI chips to various users of SCL has been made operative. This consists of import of finished semiconductor devices to meet the immediate user requirements followed by arrangements to secure diffused wafers and their packaging and testing in India. Order have been placed for the clock devices, pulse dialler, codec and microprocessors and deliveries are expected to commence in May, 1989. In